

Thermal Resistance, Junction to Ambient (Dual Operation)

t 🗊 F	Device Marking	Device	Package	Reel Size	Tape Width	Quantity
4月 -	27	FDMA1027PT	MicroFET 2x2 Thin	7 "	8 mm	3000 units

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 $R_{\theta JA}$ 

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Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	octeristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	I <sub>D</sub> = -250 μA, V <sub>GS</sub> = 0 V	-20			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	$  Breakdown Voltage Temperature Coefficient $ $I_D = -250 \ \mu A$ , referenced to 25 °C -12		-12		mV/°C	
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = -16 V, V_{GS} = 0 V$			-1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 8 V, V_{DS} = 0 V$			±100	nA
\ <i>I</i>	Cata to Source Threshold Valtage	$V = V = 1 = 250 \dots \Lambda$	0.4	07	1 2	V
$V_{GS(th)} = \Delta V_{GS(th)}$	Gate to Source Threshold Voltage           Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = -250 \ \mu A$	-0.4	-0.7	-1.3	V m\//°C
$V_{GS(th)} = \Delta V_{GS(th)} = \Delta T_J$	•	$I_D$ = -250 $\mu$ A, referenced to 25 °C	-0.4	2		
$\Delta V_{GS(th)}$	Gate to Source Threshold Voltage	$I_D$ = -250 µA, referenced to 25 °C $V_{GS}$ = -4.5 V, $I_D$ = -3.0 A	-0.4	2 90	120	
$\Delta V_{GS(th)}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_{D} = -250 \ \mu\text{A}, \text{ referenced to } 25 \ ^{\circ}\text{C}$ $V_{GS} = -4.5 \ \text{V}, \ I_{D} = -3.0 \ \text{A}$ $V_{GS} = -2.5 \ \text{V}, \ I_{D} = -2.5 \ \text{A}$	-0.4	2	120 160	mV/°C
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage	$I_D$ = -250 µA, referenced to 25 °C $V_{GS}$ = -4.5 V, $I_D$ = -3.0 A	-0.4	2 90	120	
$\frac{V_{GS(th)}}{\Delta V_{GS(th)}}$ $\frac{\Delta V_{GS(th)}}{\Delta T_J}$ $r_{DS(on)}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_{D} = -250 \ \mu\text{A}, \text{ referenced to } 25 \ ^{\circ}\text{C}$ $V_{GS} = -4.5 \ \text{V}, \ I_{D} = -3.0 \ \text{A}$ $V_{GS} = -2.5 \ \text{V}, \ I_{D} = -2.5 \ \text{A}$	-0.4	2 90 120	120 160	mV/°C
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$\begin{split} & I_D = -250 \ \mu\text{A}, \ \text{referenced to } 25 \ ^\circ\text{C} \\ & V_{GS} = -4.5 \ \text{V}, \ I_D = -3.0 \ \text{A} \\ & V_{GS} = -2.5 \ \text{V}, \ I_D = -2.5 \ \text{A} \\ & V_{GS} = -1.8 \ \text{V}, \ I_D = -1.0 \ \text{A} \\ & V_{GS} = -4.5 \ \text{V}, \ I_D = -3.0 \ \text{A} , \end{split}$	-0.4	2 90 120 172	120 160 240	mV/°C

# **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance		435	pF
Coss	Output Capacitance	V <sub>DS</sub> = -10 V, V <sub>GS</sub> = 0 V, f = 1 MHz	80	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		45	pF

# **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		9	18	ns
t <sub>r</sub>	Rise Time	$V_{DD}$ = -10 V, I <sub>D</sub> = -1.0 A $V_{GS}$ = -4.5 V, R <sub>GEN</sub> = 6 Ω	11	19	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$v_{GS} = -4.5 \text{ V}, \text{ R}_{GEN} = 6.02$	15	27	ns
t <sub>f</sub>	Fall Time		6	12	ns
Q <sub>g</sub>	Total Gate Charge		4	6	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	$V_{DD} = -10 \text{ V}, \text{ I}_{D} = -3.0 \text{ A}$ $V_{GS} = -4.5 \text{ V}$	0.8		nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge	v <sub>GS</sub> = -4.3 v	0.9		nC

# **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum continuous Drain-Source Diode Forward Current			-1.1	А
V <sub>SD</sub>	Source to Drain Diode Forward Voltage $V_{GS} = 0 V$ , $I_S = -1.1 A$ (Note 2)		-0.8	-1.2	V
t <sub>rr</sub>	Reverse Recovery Time	- I <sub>F</sub> = -3.0 A, di/dt = 100 A/μs	17		ns
Q <sub>rr</sub>	Reverse Recovery Charge	$-1_{\rm F} = -3.0$ A, di/dt = 100 A/µs	6		nC

## Notes:

1. R<sub>0,1</sub>% is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>0,1</sub> is guaranteed by design while R<sub>0CA</sub> is determined by the user's board design.



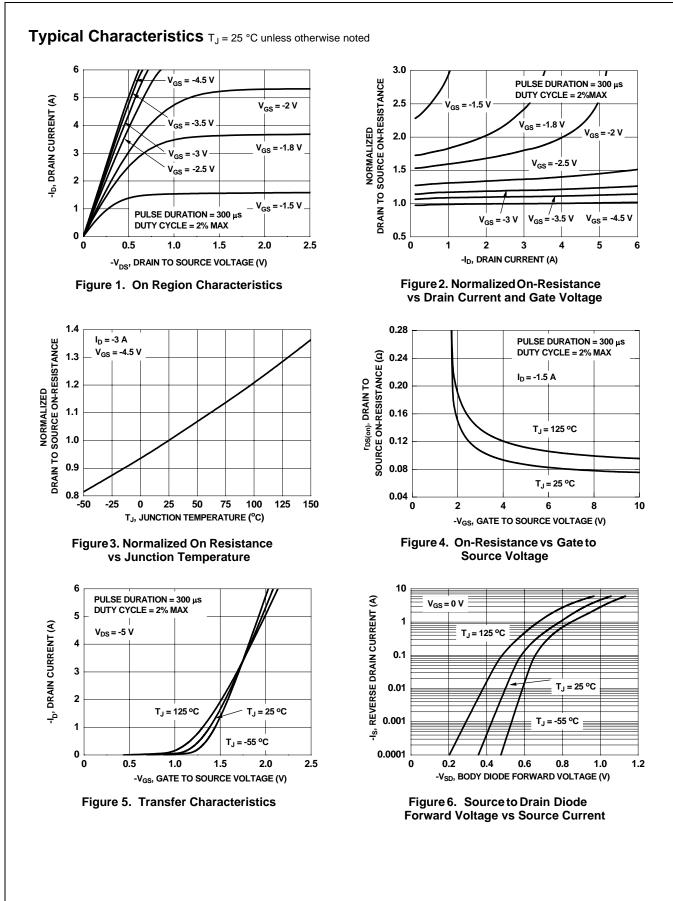
2. Pulse Test: Pulse Width < 300  $\mu s,$  Duty cycle < 2.0%.

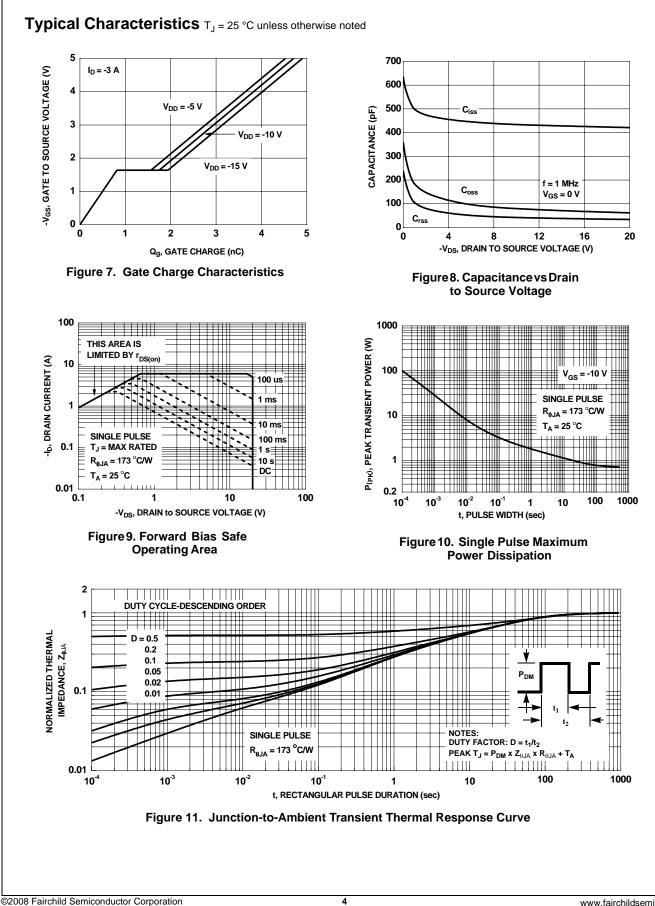
a. 86 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.

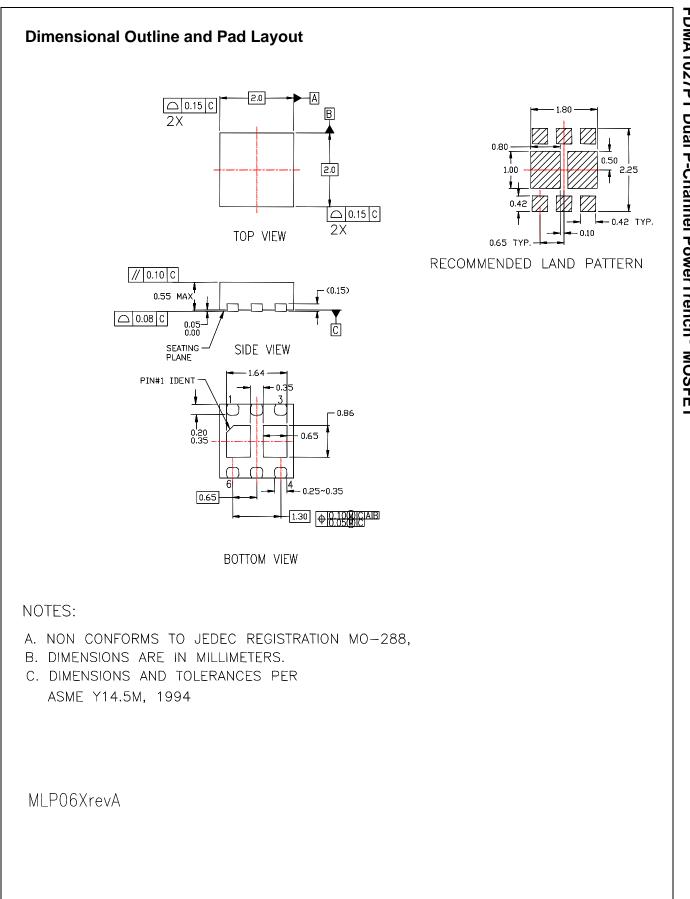
pad of 2 oz copper.

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b. 173 °C/W when mounted on a minimum pad of 2 oz copper.









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